

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/050,347
Filing Date January 15, 2002
Inventor Gurtej S. Sandhu et al.
Assignee Micron Technology, Inc.
Group Art Unit 2813
Examiner Laura M. Schillinger
Attorney's Docket No. MI22-1897
Title: Methods of Forming Transistors

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached Form PTO-1449 is submitted in compliance with 37 CFR §1.56. Pursuant to FEDERAL REGISTER, Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art are attached. No admission is made regarding whether the listed references are prior art.

Respectfully submitted,

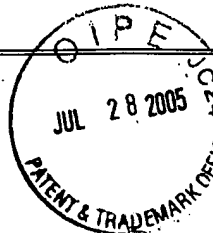
Dated:

July 28, 2005

By:

Jennifer J. Taylor
Jennifer J. Taylor, Ph.D.
Reg. No. 48,711

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PATENT AND TRADEMARK OFFICELIST OF ART CITED BY APPLICANT
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10/050,347APPLICANT
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U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	3,627,598	12/71	McDonald et al.			
	AB	4,254,161	03/81	Kemlage			
	AC	4,262,631	04/81	Kubacki			
	AD	4,435,447	03/84	Ito et al.			
	AE	4,882,649	11/89	Chen et al.			
	AF	4,891,684	01/90	Nishioka et al.			
	AG	4,980,307	12/90	Ito et al.			
	AH	4,996,081	02/91	Ellul et al.			
	AI	5,051,794	09/91	Mori			
	AJ	5,142,438	08/92	Reinberg et al.			

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							Yes	No
	AK	EP 0886308 A2	12/98	EPO				
	AL	237243 a	04/01	Japan				
	AM							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AN	Wolf, Stanley, <i>Silicon Processing for the VLSI Era</i> (1995), V.3, 648-9
	AO	Laughery et al., <i>Effect of H₂ Content on Reliability of Ultrathin In-Situ Steam Generated (ISSG) SiO₂</i> , Sept., 2000, Vol. 21, No. 9.
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EXAMINER

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	AA	5,227,651	07/93	Kim et al.			
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	AC	5,324,679	06/94	Kim et al.			
	AD	5,330,936	07/94	Ishitani			
	AE	5,350,707	09/94	Ko et al.			
	AF	5,376,593	12/94	Sandhu et al.			
	AG	5,393,702	02/95	Yang et al.			
	AH	5,397,748	03/95	Watanabe et al.			
	AI	5,398,641	03/95	Shih			
	AJ	5,459,105	10/95	Matsuura			

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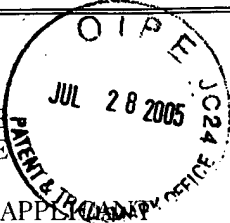
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				FILING DATE January 15, 2002		GROUP 2813	



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	AA	5,498,890	03/96	Kim et al.			
	AB	5,504,029	04/96	Murata et al.			
	AC	5,508,542	04/96	Geiss et al.			
	AD	5,523,596	06/96	Ohi et al.			
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	AH	5,851,603	12/98	Tsai et al.			
	AI	5,882,978	03/99	Srinivasan et al.			
	AJ	6,001,741	12/99	Alers			

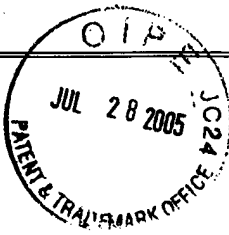
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	AA	6,001,748	12/99	Tanaka			
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	AC	6,051,865	04/00	Gardner et al.			
	AD	6,063,713	06/00	Doan			
	AE	6,077,754	06/00	Srinivasan et al.			
	AF	6,096,597	08/00	Tsu et al.			
	AG	6,111,744	08/00	Doan			
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	AA	6,348,420 B1	02/02	Raaijmakers et al.			
	AB	6,265,327	07/01	Kobayashi et al.			
	AC	6,350,707 B1	02/02	Liu et al.			
	AD	6,723,599 B2	04/04	Eppich et al.			
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